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## ISSN: 2349-5162 | ESTD Year: 2014 | Monthly Issue



## JOURNAL OF EMERGING TECHNOLOGIES AND INNOVATIVE RESEARCH (JETIR)

An International Scholarly Open Access, Peer-reviewed, Refereed Journal

Ref No: JETIR / Vol 6 / Issue 5 / 012

**Confirmation Letter** 

To,

Dr. Rakesh Kumar

Published in : Volume 6 | Issue 5 | 2019-05-01



Subject: Publication of paper at International Journal of Emerging Technologies and Innovative Research.

Dear Author,

With Greetings we are informing you that your paper has been successfully published in the International Journal of Emerging Technologies and Innovative Research (ISSN: 2349-5162). Following are the details regarding the published paper.

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Published in : Volume 6 | Issue 5 | 2019-05-01

Publication Date: 2019-05-01 Page No : 57-59

Published URL: http://www.jetir.org/view?paper=JETIRCW06012

: Dr. Rakesh Kumar

Thank you very much for publishing your article in JETIR. We would appreciate if you continue your support and keep sharing your knowledge by writing for our journal JETIR.















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